

ABSTRACT

A deviation measurement device, which is used for measuring the deviation between the center (O) of a substrate (W) and a standard center (O'), and comprises a reference arm (101), a moving arm (103) and a first linear module (102), wherein the moving arm (103) is provided with a first positioning claw (104), and the first positioning claw (104) is used for abutting against two points on an edge of the substrate (W); the reference arm (101) is provided with a second positioning claw (105), and the second positioning claw (105) is used for abutting against two points on the edge of the substrate (W); and the moving arm (103) is arranged opposite the reference arm (101). A connecting line between the center (x1) of the first positioning claw (104) and the center (x2) of the second positioning claw (105) is a straight line L, and the straight line L passes through the standard center (O'); the moving arm (103) can translate along the straight line L under the driving of the first linear module(102); and the first positioning claw (104) pushes the substrate (W) until the first positioning claw (104) and the second positioning claw (105) are simultaneously brought into contact with the edge of the substrate, and at this time, the center (O) of the substrate is located on the straight line L. The deviation between the center (O) of the substrate and the standard center (O') can be calculated according to the coordinates of the reference arm (101) and the coordinates of the moving arm (103). The substrate (W) may be an oval substrate or a circular substrate having a notch or a flat edge.